

**Features**

- Uses CRM(CQ) advanced Trench technology
- Extremely low on-resistance  $R_{DS(on)}$
- Excellent  $Q_g \times R_{DS(on)}$  product(FOM)
- Complementary N-ch and P-ch MOSFET

**Product Summary**

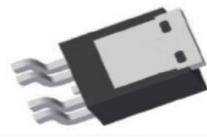
Symbol	N-Ch	P-Ch
$V_{DS}$	100V	-100V
$R_{DS(on)}$ typ.	71mΩ	67mΩ
$I_D$	10A	-10A

**Applications**

- Motor drive

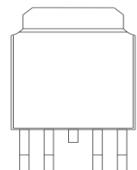
**100% DVDS Tested****100% Avalanche Tested****TO-252-5**

Top View

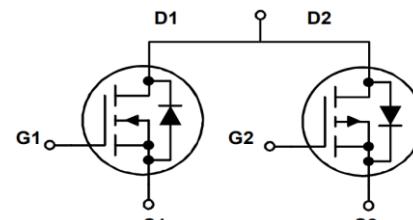


Bottom View

D1/D2



Top View



N-Channel

P-Channel

**Package Marking and Ordering Information**

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRMV1004C	CRMV1004C	TO-252-5	Taping	N/A	N/A	2500pcs

**Absolute Maximum Ratings**

Parameter	Symbol	Maximum		Unit
		N-Ch	P-Ch	
Drain-source voltage	$V_{DS}$	100	-100	V
Continuous drain current $T_C = 25^\circ\text{C}$ (Silicon limit)	$I_D$	29	-29	A
Continuous drain current $T_C = 25^\circ\text{C}$ (Package limit)	$I_D$	10	-10	A
Pulsed drain current ( $T_C = 25^\circ\text{C}$ , $t_p$ limited by $T_{jmax}$ )	$I_{D\text{ pulse}}$	40	-40	A
Avalanche energy, single pulse ( $L=0.5\text{mH}$ , $R_g=25\Omega$ )	$E_{AS}$	42	156	mJ
Gate-Source voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Power dissipation ( $T_C = 25^\circ\text{C}$ )	$P_{tot}$	57.8	57.8	W
Operating junction and storage temperature	$T_j, T_{stg}$	-55...+150		°C

**Thermal Resistance**

Parameter	Symbol	Typ	Max	Unit
Thermal resistance, junction - case.	R <sub>thJC</sub>	1.5	2.2	°C/W
SMD version, device on PCB <sup>1</sup>	R <sub>thJA</sub>	80.4	96.5	°C/W
Thermal resistance, junction - ambient(min. footprint)				

## NOTE:

1.The value of R<sub>θJA</sub> is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub> =25°C. The value in any given application depends on the user's specific board design.

**N-Channel Electrical Characteristic (at T<sub>j</sub> = 25 °C, unless otherwise specified)**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

**Static Characteristic**

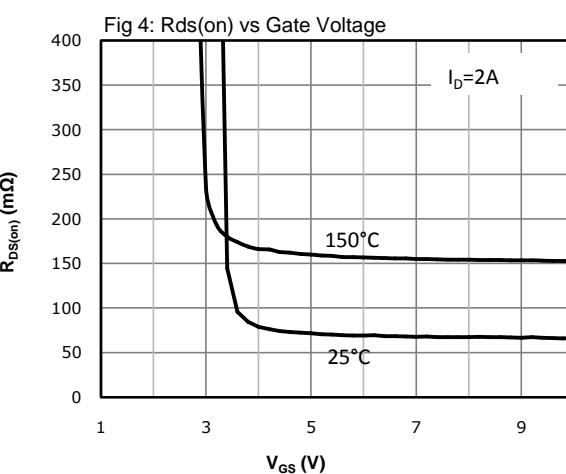
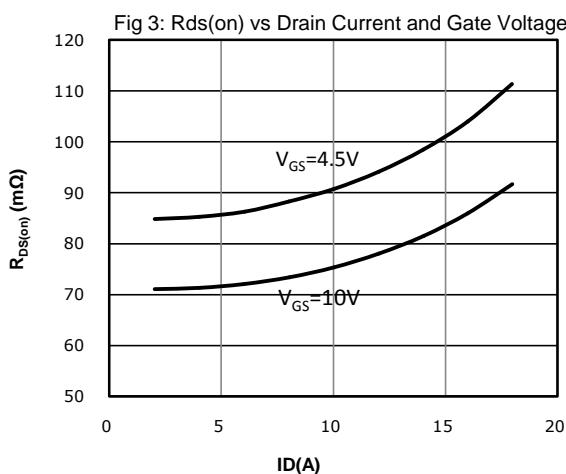
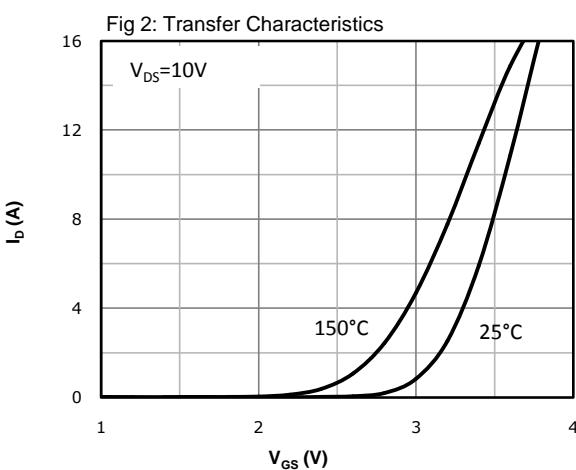
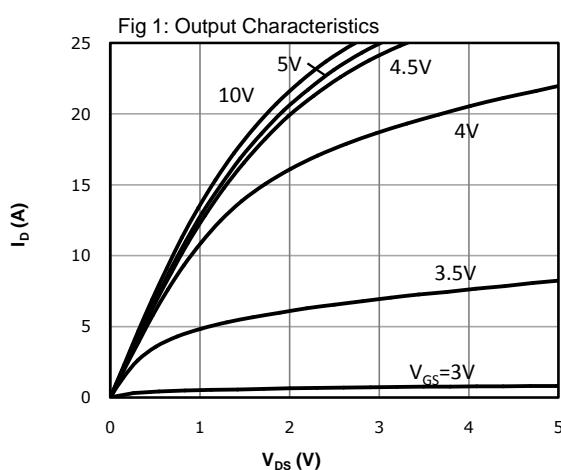
Drain-source breakdown voltage	BV <sub>DSS</sub>	100	-	-	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA
Gate threshold voltage	V <sub>GS(th)</sub>	1.5	2.2	2.9	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Zero gate voltage drain current	I <sub>DSS</sub>	-	0.08	1	μA	V <sub>DS</sub> =40V, V <sub>GS</sub> =0V T <sub>j</sub> =25°C T <sub>j</sub> =125°C
Gate-source leakage current	I <sub>GSS</sub>	-	±10	±100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Drain-source on-state resistance	R <sub>DS(on)</sub>	-	85.0	102.0	mΩ	V <sub>GS</sub> =4.5V, I <sub>D</sub> =2A
		-	71.0	85.0		V <sub>GS</sub> =10V, I <sub>D</sub> =2A
Transconductance	g <sub>f</sub>	-	11	-	S	V <sub>DS</sub> =10V, I <sub>D</sub> =2A

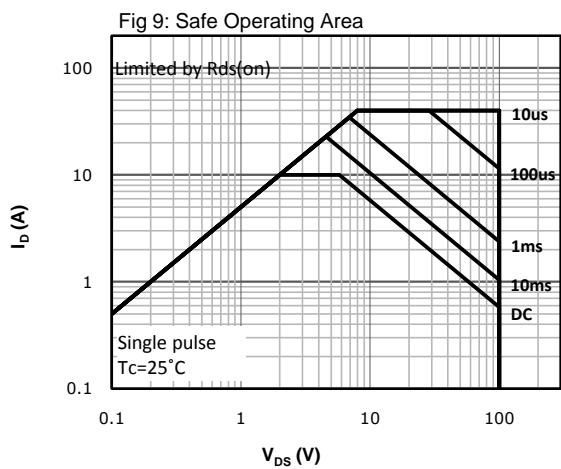
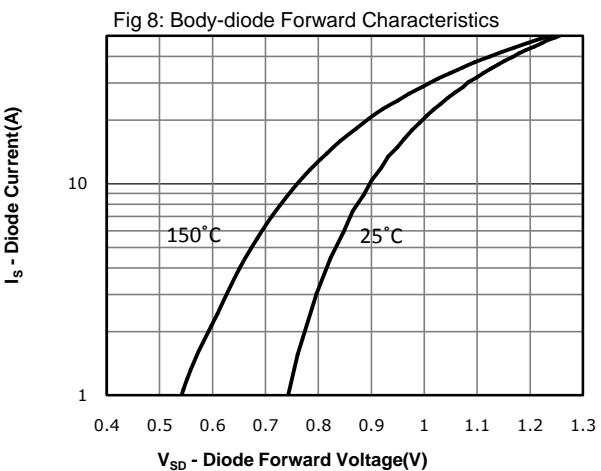
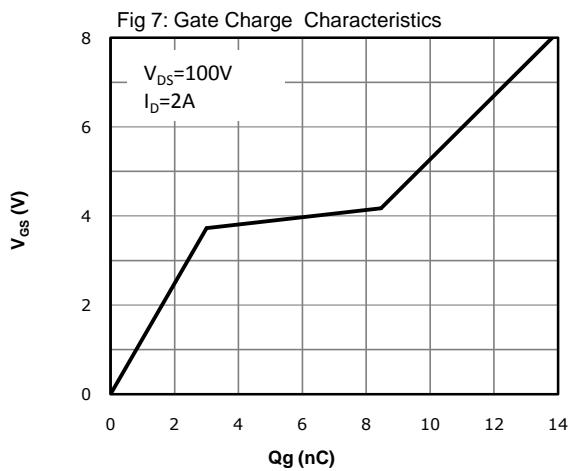
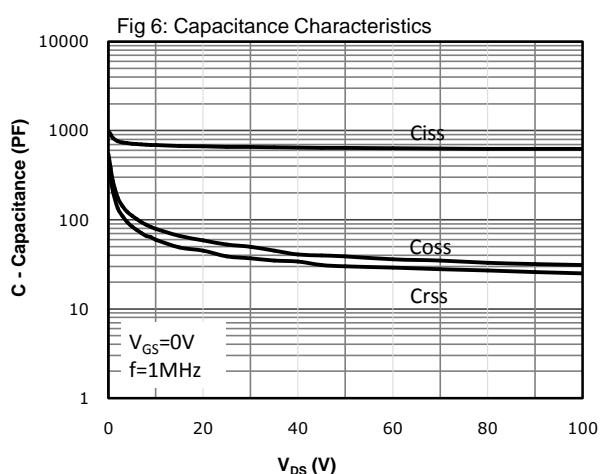
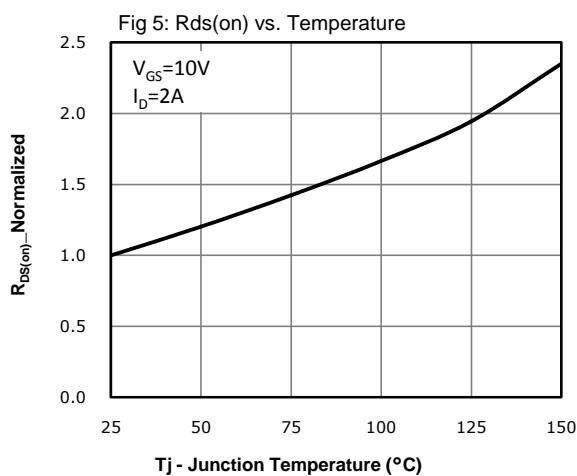
**Dynamic Characteristic**

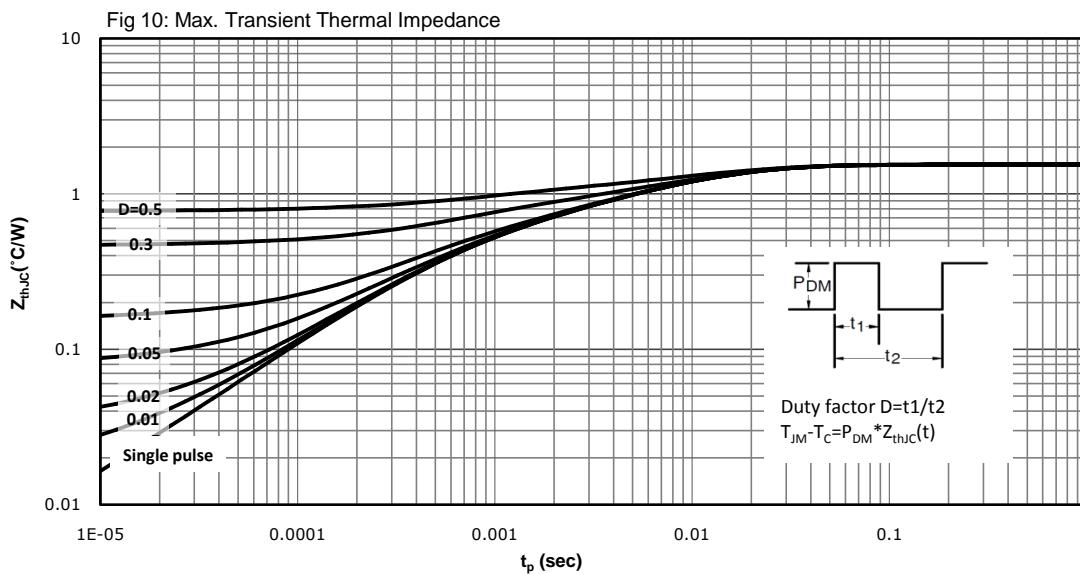
Input Capacitance	C <sub>iss</sub>	-	620	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =100V, f=1MHz
Output Capacitance	C <sub>oss</sub>	-	31	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	23	-		
Gate Total Charge	Q <sub>G</sub>	-	16.5	-	nC	V <sub>GS</sub> =10V, V <sub>DS</sub> =100V, I <sub>D</sub> =2A, f=1MHz
Gate-Source charge	Q <sub>gs</sub>	-	2.9	-		
Gate-Drain charge	Q <sub>gd</sub>	-	5.4	-		
Turn-on delay time	t <sub>d(on)</sub>	-	7.1	-		
Rise time	t <sub>r</sub>	-	4.7	-		
Turn-off delay time	t <sub>d(off)</sub>	-	18.2	-		
Fall time	t <sub>f</sub>	-	13.3	-	ns	V <sub>GS</sub> =10V, V <sub>DD</sub> =50V, R <sub>G_ext</sub> =2.7Ω, ID=2A
Gate resistance	R <sub>G</sub>	-	1.9	-		

**Body Diode Characteristic**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	$V_{SD}$	-	0.78	1.20	V	$V_{GS}=0V, I_{SD}=2A$
Body Diode Reverse Recovery Time	$t_{rr}$	-	19.7	-	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$	-	17.9	-	nC	$I_F=2A, dI/dt=100A/\mu s$

**N-Channel Typical Performance Characteristics**





**P-Channel Electrical Characteristic (at  $T_j = 25^\circ\text{C}$ , unless otherwise specified)**

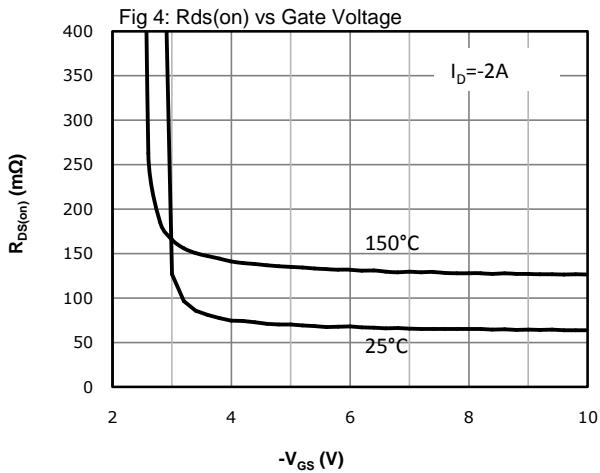
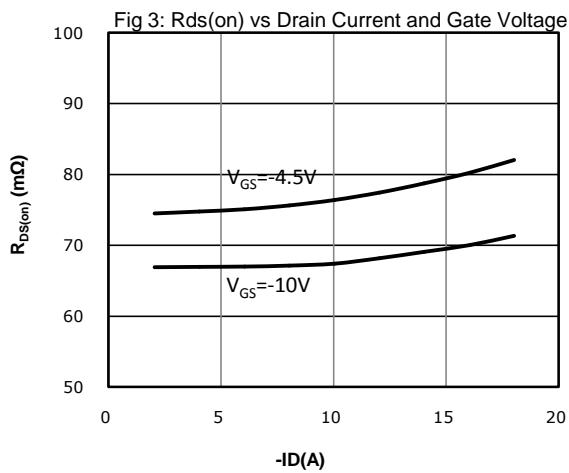
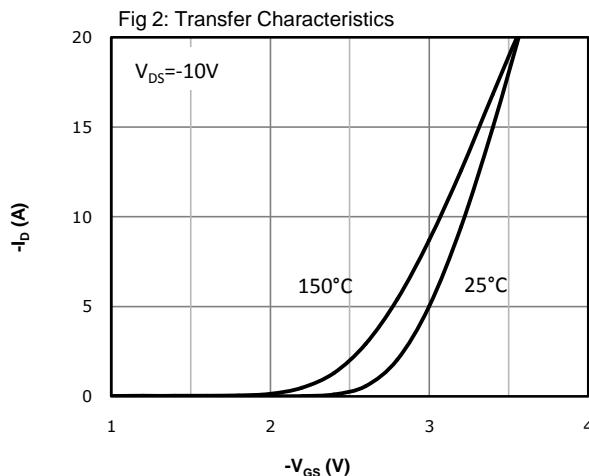
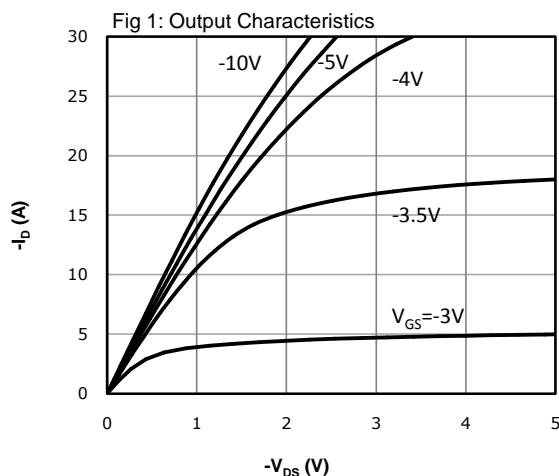
Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
<b>Static Characteristic</b>						
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	-100	-	-	V	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=-250\mu\text{A}$
Gate threshold voltage	$\text{V}_{\text{GS}(\text{th})}$	-1.3	-2	-2.7	V	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=-250\mu\text{A}$
Zero gate voltage drain current	$\text{I}_{\text{DSS}}$	-	-0.08	-1	$\mu\text{A}$	$\text{V}_{\text{DS}}=-40\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_j=25^\circ\text{C}$ $T_j=125^\circ\text{C}$
Gate-source leakage current	$\text{I}_{\text{GSS}}$	-	$\pm 10$	$\pm 100$	nA	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$
Drain-source on-state resistance	$\text{R}_{\text{DS}(\text{on})}$	-	75.0	90.0	$\text{m}\Omega$	$\text{V}_{\text{GS}}=-4.5\text{V}, \text{I}_D=-2\text{A}$
		-	67.0	80.0		$\text{V}_{\text{GS}}=-10\text{V}, \text{I}_D=-2\text{A}$
Transconductance	$\text{g}_{\text{fs}}$	-	11.3	-	S	$\text{V}_{\text{DS}}=-10\text{V}, \text{I}_D=-2\text{A}$

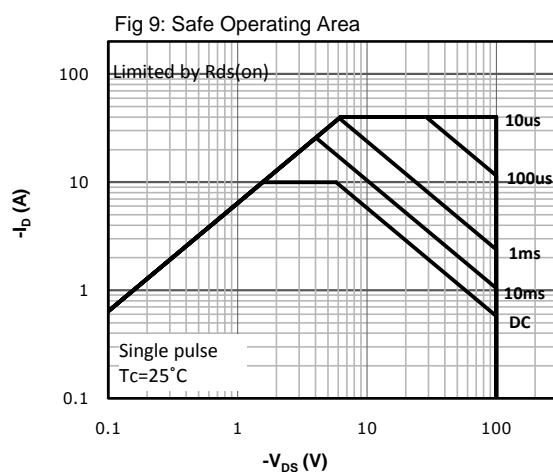
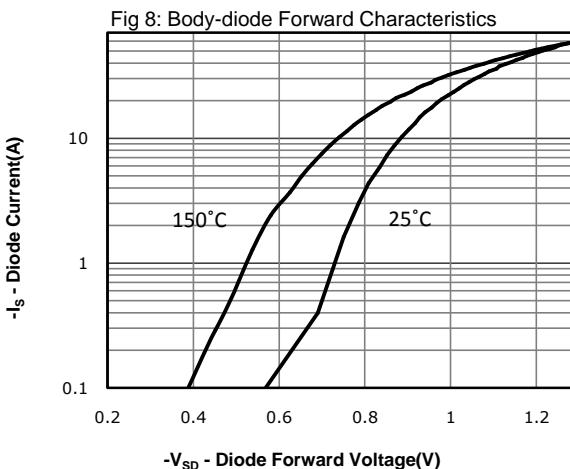
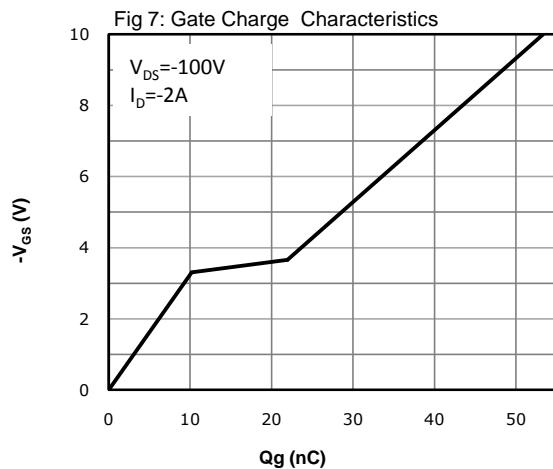
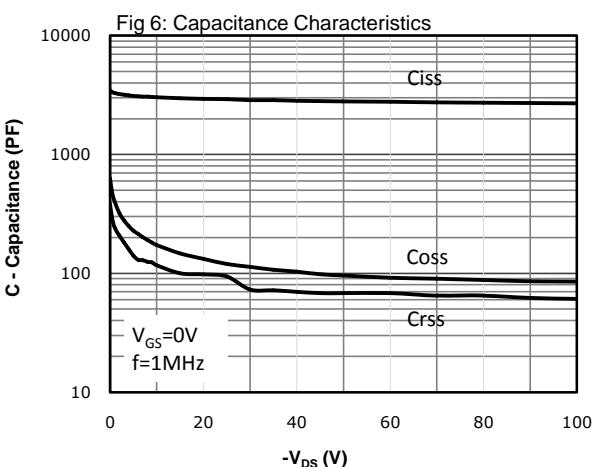
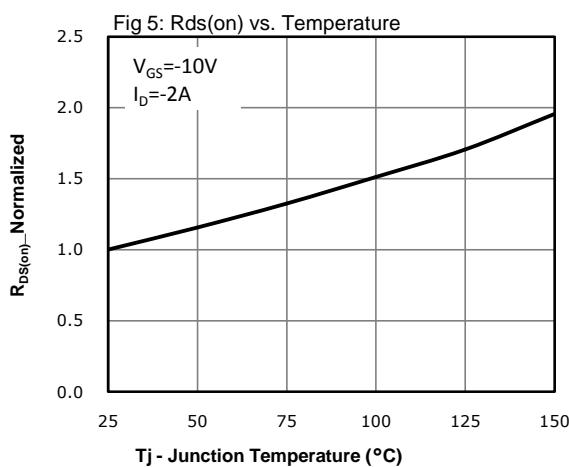
**Dynamic Characteristic**

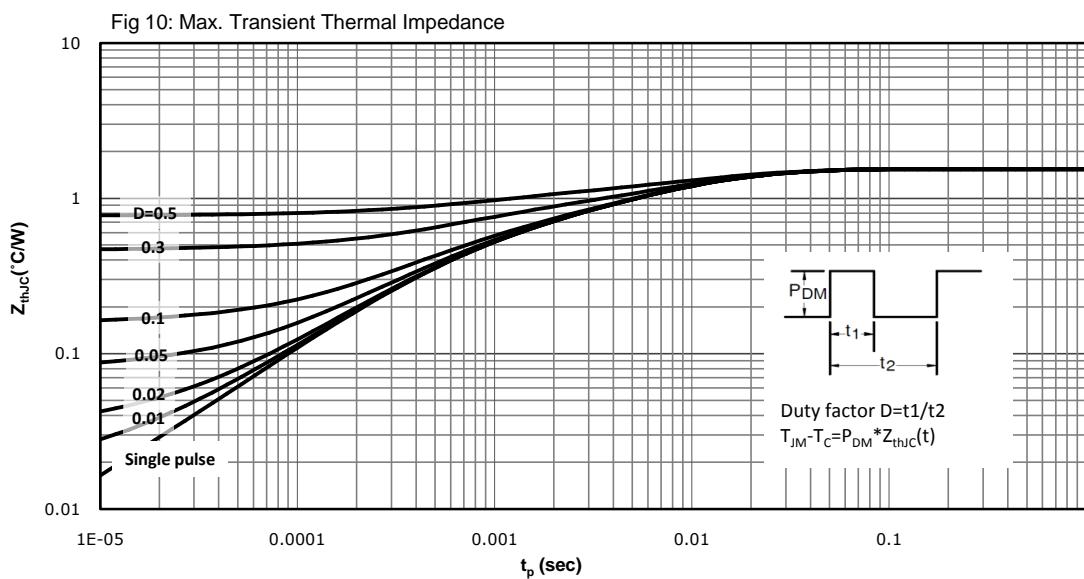
Input Capacitance	$\text{C}_{\text{iss}}$	-	2703	-	pF	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=-100\text{V}, f=1\text{MHz}$
Output Capacitance	$\text{C}_{\text{oss}}$	-	85	-		
Reverse Transfer Capacitance	$\text{C}_{\text{rss}}$	-	63	-		
Gate Total Charge	$\text{Q}_G$	-	53	-	nC	$\text{V}_{\text{GS}}=-10\text{V}, \text{V}_{\text{DS}}=-100\text{V}, \text{I}_D=-2\text{A}, f=1\text{MHz}$
Gate-Source charge	$\text{Q}_{\text{gs}}$	-	10.0	-		
Gate-Drain charge	$\text{Q}_{\text{gd}}$	-	11.8	-		
Turn-on delay time	$t_{\text{d}(\text{on})}$	-	8.0	-	ns	$\text{V}_{\text{GS}}=-10\text{V}, \text{V}_{\text{DD}}=-50\text{V}, \text{R}_{\text{G\_ext}}=2.7\Omega, \text{ID}=-2\text{A}$
Rise time	$t_r$	-	7.7	-		
Turn-off delay time	$t_{\text{d}(\text{off})}$	-	131.8	-		
Fall time	$t_f$	-	49.5	-		
Gate resistance	$\text{R}_G$	-	19.7	-	$\Omega$	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, f=1\text{MHz}$

**Body Diode Characteristic**

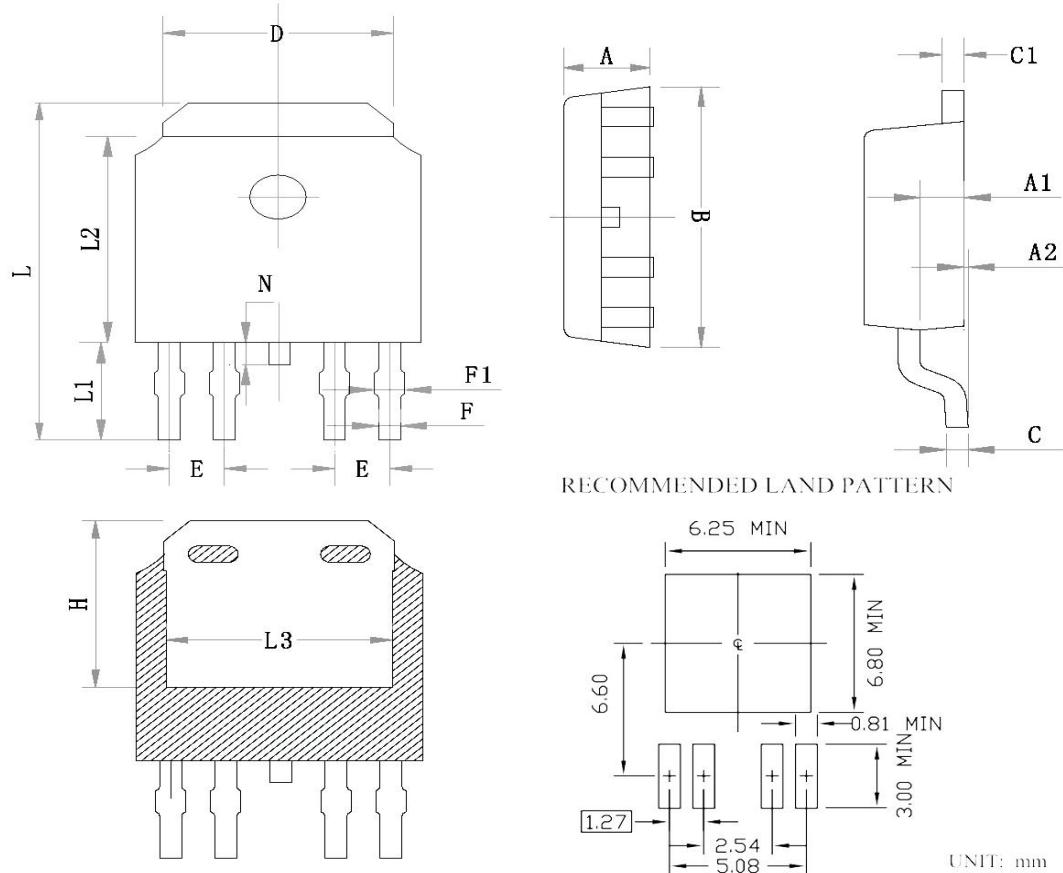
Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		
Body Diode Forward Voltage	$V_{SD}$	-	-0.78	-1.20	V	$V_{GS}=0V, I_{SD}=-2A$
Body Diode Reverse Recovery Time	$t_{rr}$	-	23.4	-	ns	$I_F=2A, dI/dt=100A/\mu s$
Body Diode Reverse Recovery Charge	$Q_{rr}$	-	23.3	-	nC	

**P-Channel Typical Performance Characteristics**





### Package Outline: TO252-5



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	2.20	2.30	2.40	0.087	0.091	0.094
A1	0.91	1.01	1.11	0.036	0.040	0.044
A2	0.00	----	0.25	0.000	----	0.010
B	6.40	6.60	6.80	0.252	0.260	0.268
C	0.45	0.50	0.58	0.018	0.020	0.023
C1	0.45	0.50	0.58	0.018	0.020	0.023
D	5.12	5.32	5.52	0.202	0.209	0.217
E	1.27 BSC			0.050 BSC		
F	0.40	0.50	0.60	0.016	0.020	0.024
F1	0.45	0.65	0.80	0.018	0.026	0.031
H	4.57	4.85	5.10	0.180	0.191	0.201
L	9.40	9.90	10.20	0.370	0.390	0.402
L1	2.40	2.75	3.00	0.094	0.108	0.118
L2	5.40	5.80	6.25	0.213	0.228	0.246
L3	5.00	5.30	5.50	0.197	0.209	0.217
N	0.45	----	1.20	0.018	----	0.047

#### NOTE

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.  
MOLD FLASH SHOULD BE LESS THAN 6MIL
2. DIMENSION L IS MEASURED IN GAUGE PLANE.
3. TOLERANCE 0.10mm UNLESS OTHER WISE SPECIFIED.
4. CONTROLLING DIMENSION IS MILLIMETER.  
CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



华润微电子(重庆)有限公司

CRMV1004C

100V Complementary Power MOSFET

## Revision History

Revison	Date	Major changes
1.1	2022/12/15	Release of formal version

## Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

This product is suitable for reflow soldering up to 260°C, not very suitable for wave soldering.

The reliability of this product is not guaranteed under specific conditions when accepted by customers.

CRM(CQ) reserves the right to improve product design, function and reliability without notice.